Welcome to Galaxy Examinator reports

Date: Mon Sep 2 15:44:56 2024
Product :
LotID :

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Tests Statistics

Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Cp	Cpk	Yield
78	Functional_T8	P	n/a .	n/a .	Summary	6	3	n/a .	0	n/a .	n/a .	50.00 %

Pareto of Tests Cp

Test	Name	Cp	Test Cp Chart

Shows all Cp <= 1.7 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests Cpk

Test	Name	Cpk	Test Cpk Chart

Shows all Cpk <= 1.3 (Defined in Options , section 'Pareto/Define Cp cut−off limit')

Pareto of Tests failures

Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
78	Functional_T8	–	3	50.0 %	n/a	n/a	████████████
–	**Cumul. of failures**	**–**	**3**	**50.0 %**	**0.0 %**	**0.0 %**	

–– Yield loss: number of failed test executions / number of parts

–– Fail contribution: number of failed test executions / number of parts failed

–– Test Fail rate: number of failed test executions / number of test executions

Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **6**
Total patterns detected: **0**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut−off limit')

No Functional failure signature detected

Possible root cause: The 'Options/Data processing/Multi−results...' option is set to 'merge' instead of 'no merge'

Pareto of Parametric Failure Signatures (tests failing concurrently)

Pareto of Software Bins

Software Binning	Bin Name	Count	Percentage	Software Binning Chart
1	–	6	100.0 %	
Cumul.	**Cumul.**	**6**	**100.0%**	

Pareto of Hardware Bins

Hardware Binning	Bin Name	Count	Percentage	Hardware Binning Chart
1	–	6	100.0 %	
Cumul.	Cumul.	6	100.0%	

Wafermaps & Strip Maps

Map type	Show Software bins
Devices tested (with retests)	6

List of Individual Maps

Top 10 Software Binning	1
Color	🟩
Pass/Fail	–
Percentage	100.0%
Total count	6

Map style	WAFER map (parts tested are DIES)
Total physical parts tested	0
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Warning	No Wafermap data available

Software Binning Summary

Software Binning	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
1	–	–	6	100.0 %	██████████████
ALL Bins	**ALL Bins**	**–**	**6**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Hardware Binning Summary

Hardware Binning	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
1	–	–	6	100.0 %	
ALL Bins	ALL Bins	–	**6**	**100.0 %**	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Message Log

No log message to report

Global Information

Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Mon Sep 02 15:44:56 2024
Data processed	4.1 KB (4193 bytes)
Processing time	3.00 seconds
Processing speed	1.4 KB/sec
Examinator expires	Sat Sep 2 2034
(null)	–
File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/results_v1.std
Tests mapping file	n/a
Setup time	Tue Sep 03 03:33:58 2024
Start time	Tue Sep 03 02:53:56 2024

End time	Tue Sep 03 03:33:58 2024
Test duration	40 minutes 02 seconds
Product	n/a
Program	rahmana_i8243_p1.igxl
Revision	n/a
Lot	n/a
Sub−Lot	n/a
WaferID	n/a
Parts processed	All Data / parts (any Bin)
Data from Sites	All sites
Test time (GOOD parts)	n/a .
Test time (ALL parts)	n/a .
Average test time	400.333 sec. / device (includes tester idle time between parts)
Total parts tested	6 − Includes parts retested (if any)
Good parts (Yield)	6 (100.00%) − Includes parts retested (if any)
Bad parts (Yield loss)	0 (0.00%) − Includes parts retested (if any)
Parts retested	n/a .
Parts aborted	0 (0.00%)
(null)	−
STDF Version	4.0
Tester name	SNG−UFP−789
Tester type	UltraFLEXplus
Station	1
Part type	n/a
Operator	rahmana
Exec_type	IG−XL
Exec_version	10.30.10_uflx (P1.11)
TestCode	n/a
Test Temperature	n/a
User Text	n/a
Aux_file	n/a
Package type	n/a
Per_freq	n/a
Spec_name	n/a
Spec_version	n/a
Family ID	n/a
Date code	n/a
Design Rev	n/a

Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	–
Site details	Site# 0

Global Options

Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift